Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/609,062	VENK, SRIDHARAN	
Examiner	Art Unit	
Tianjie Chen	2656	

	SEARCHED				
Class	Subclass	Date	Examiner		
360	264.2				
361	685		_		
29	840				
156	250				
257	692	3/1/2006	TJ		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Report	3/1/2006	TJ